D²PAK (TO-263)



N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY						
V_{DS} (V) at T_{J} max.	650					
R _{DS(on)} max. (Ω) at 25 °C	$V_{GS} = 10 V$	0.19				
Q _g max. (nC)	106					
Q _{gs} (nC)	14					
Q _{gd} (nC)	33					
Configuration	Single					

FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Q_a)
- Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
- Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Consumer and computing - ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \text{ °C}$, unless otherwise noted)									
PARAMETER			SYMBOL	LIMIT	UNIT				
Drain-Source Voltage			V _{DS}	650	v				
Gate-Source Voltage			V _{GS}	± 30	l v				
Continuous Drain Current (T _J = 150 °C)	V _{GS} at 10 V	T _C = 25 °C T _C = 100 °C		20					
	VGS at 10 V	T _C = 100 °C	ID	13	А				
Pulsed Drain Current ^a			I _{DM}	60					
Linear Derating Factor				1.7	W/°C				
Single Pulse Avalanche Energy ^b			E _{AS}	367	mJ				
Maximum Power Dissipation			PD	208	W				
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C				
Drain-Source Voltage Slope	T _J = 1	$T_J = 125 \text{ °C}$		37	1//22				
Reverse Diode dV/dt ^d			dV/dt	31	V/ns				
Soldering Recommendations (Peak Temperature) ^c	for 10 s			300	°C				

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 5.1 A.

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c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.





THERMAL RESISTANCE RAT	NGS							
PARAMETER	SYMBOL	TYP. MAX.				UNIT		
Maximum Junction-to-Ambient	R _{thJA}	- 62						
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.5				°C/W		
SPECIFICATIONS (T _J = 25 °C, u	unless otherw	ise noted)						
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static					1	I	1	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D =	250 µA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C	, I _D = 1 mA	-	0.67	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V
Osta Osumas Laskana		$V_{GS} = \pm 20 V$		-	-	± 100	nA	
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 30 \text{ V}$		-	-	± 1	μA
Zara Cata Valtara Drain Current		V _{DS} =	= 520 V, V ₀	_{GS} = 0 V	-	-	1	μA
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 520 \	$V, V_{GS} = 0$	V, T _J = 125 °C	-	-	500	
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$		I _D = 11 A	-	0.19	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 30 V, I _D	= 11 A	-	7.0	-	S
Dynamic	•							
Input Capacitance	C _{iss}		V _{GS} = 0 V, V _{DS} = 100 V,		-	2322	-	
Output Capacitance	C _{oss}				-	105	-	
Reverse Transfer Capacitance	C _{rss}	f = 1 MHz		-	4	-	pF	
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	N		-	84	-		
Effective Output Capacitance, Time Related ^b	C _{o(tr)}	$v_{\rm DS} = 0.0$	$V_{DS} = 0 V$ to 520 V, $V_{GS} = 0 V$		-	293	-	
Total Gate Charge	Qg		V _{GS} = 10 V I _D = 11 A, V _{DS} = 520 V		-	71	106	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V			-	14	-	
Gate-Drain Charge	Q _{gd}				-	33	-	
Turn-On Delay Time	t _{d(on)}		V_{DD} = 520 V, I_D = 11 A, V_{GS} = 10 V, R_g = 9.1 Ω		-	22	44	ns
Rise Time	t _r	V _{DD} =			-	34	68	
Turn-Off Delay Time	t _{d(off)}	V _{GS} :			-	68	102	
Fall Time	t _f				-	42	84	
Gate Input Resistance	R _g	f = 1 MHz, open drain		-	0.78	-	Ω	
Drain-Source Body Diode Characteristi	cs							
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	MOSFET symbol showing the		-	-	21	
Pulsed Diode Forward Current	I _{SM}	integral reverse p - n junction diode			-	-	53	A
Diode Forward Voltage	V _{SD}	T _J = 25 °	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V			0.9	1.2	V
Reverse Recovery Time	t _{rr}		$T_J = 25 \text{ °C}, I_F = I_S = 11 \text{ A},$ dI/dt = 100 A/µs, V _R = 25 V		-	160	-	ns
Reverse Recovery Charge	Q _{rr}	$T_J = 2$			-	1.2	-	μC
Reverse Recovery Current	I _{RRM}	ai/at =			-	14	-	A
,					1	i	1	

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

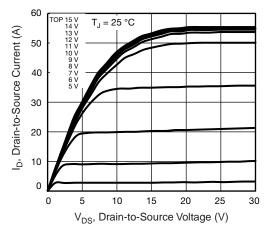


Fig. 1 - Typical Output Characteristics

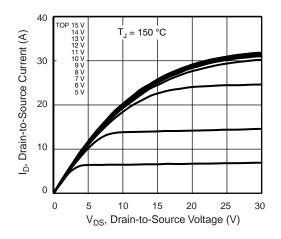


Fig. 2 - Typical Output Characteristics

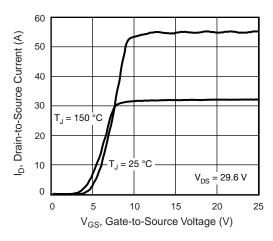


Fig. 3 - Typical Transfer Characteristics

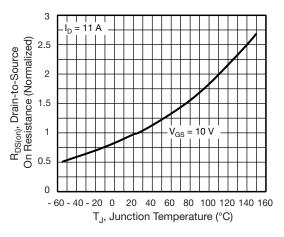


Fig. 4 - Normalized On-Resistance vs. Temperature

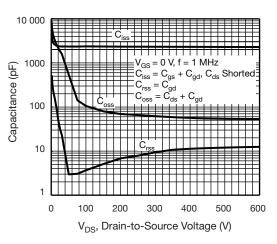


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

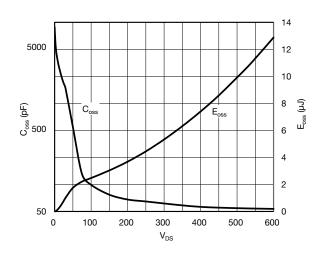


Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}

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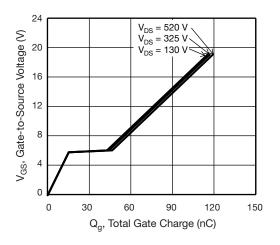


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

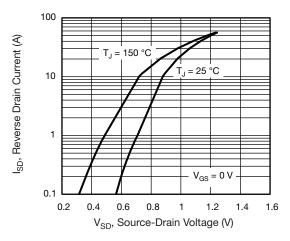


Fig. 8 - Typical Source-Drain Diode Forward Voltage

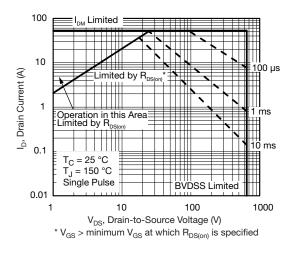


Fig. 9 - Maximum Safe Operating Area

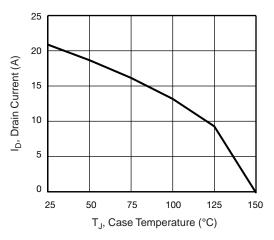


Fig. 10 - Maximum Drain Current vs. Case Temperature

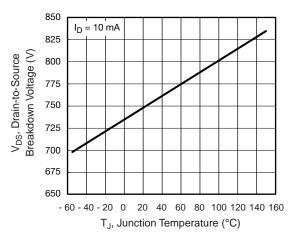


Fig. 11 - Temperature vs. Drain-to-Source Voltage



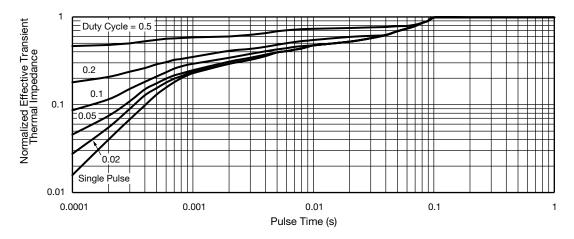


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

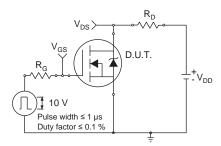


Fig. 13 - Switching Time Test Circuit

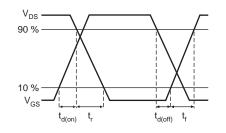


Fig. 14 - Switching Time Waveforms

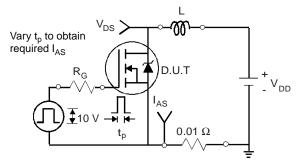


Fig. 15 - Unclamped Inductive Test Circuit

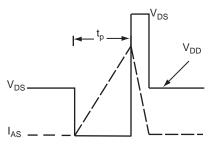


Fig. 16 - Unclamped Inductive Waveforms

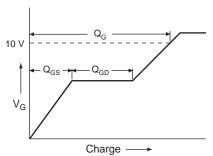
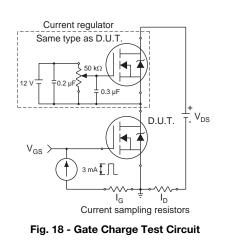
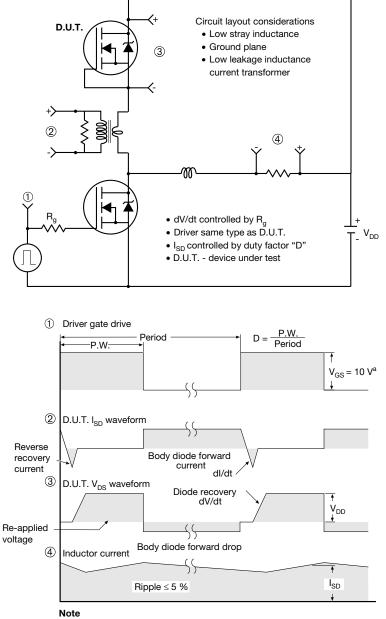


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit

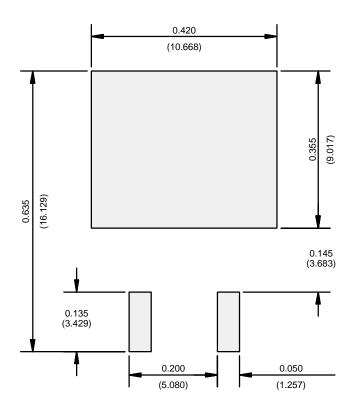


a. $V_{GS} = 5$ V for logic level devices

Fig. 19 - For N-Channel



RECOMMENDED MINIMUM PADS FOR D²PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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